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Second edition  
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## **Optics and photonics — Lasers and laser-related equipment — Test methods for laser beam power (energy) density distribution**

*Optique et photonique — Lasers et équipements associés aux lasers — Méthodes d'essai de distribution de la densité de puissance (d'énergie) du faisceau laser*



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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see [www.iso.org/patents](http://www.iso.org/patents)).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the WTO principles in the Technical Barriers to Trade (TBT) see the following URL: [Foreword - Supplementary information](#)

The committee responsible for this document is ISO/TC 172, *Optics and photonics*, Subcommittee SC 9, *Electro-optical systems*.

This second edition cancels and replaces the first edition (ISO 13694:2000), which has been technically revised with the following changes:

- a) the definition of power density distribution  $E(x, y, z)$  has been revised, a definition of the power density  $E(x_0, y_0, z)$  has been added;
- b) the definition of energy density distribution  $H(x, y, z)$  has been revised, a definition of the energy density  $H(x_0, y_0, z)$  has been added;
- c) the term "threshold power [energy] density" has been replaced by "clip-level power [energy] density". The index "T" indicating "threshold" has been replaced by "CL" accordingly;
- d) the term "effective power [energy]" has been replaced by "clip-level power [energy]";
- e) in [3.2.5](#), the formula for beam ellipticity has been revised;
- f) the term "effective irradiation area" has been replaced by "clip-level irradiation area";
- g) the notation  $E_{\eta}(z)$  [ $H_{\eta}(z)$ ] indicating the clip-level average power [energy] density has been replaced by  $E_{\eta\text{ave}}(z)$ , [ $H_{\eta\text{ave}}(z)$ ];
- h) [Figure 1](#) has been revised taking into account the items a) and g) of this list.

It also incorporates the corrigendum ISO 13694:2000/Cor 1:2005.

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## Introduction

Many applications of lasers involve using the near-field as well as the far-field power [energy] density distribution of the beam. The power [energy] density distribution of a laser beam is characterized by the spatial distribution of irradiant power [energy] density with lateral displacement in a particular plane perpendicular to the direction of propagation. In general, the power [energy] density distribution of the beam changes along the direction of propagation. Depending on the power [energy], size, wavelength, polarization, and coherence of the beam, different methods of measurement are applicable in different situations. Five methods are commonly used: camera arrays (1D and 2D), apertures, pinholes, slits, and knife edges.

This International Standard provides definitions of terms and symbols to be used in referring to power density distribution, as well as requirements for its measurement. For pulsed lasers, the distribution of time-integrated power density (i.e. energy density) is the quantity most often measured.

According to ISO 11145, it is possible to use two different definitions for describing and measuring the laser beam diameter. One definition is based on the measurement of the encircled power [energy]; the other is based on determining the spatial moments of the power [energy] density distribution of the laser beam.

The use of spatial moments is necessary for calculating the beam propagation factor,  $K$ , and the beam propagation ratio,  $M^2$ , from measurements of the beam widths at different distances along the propagation axis. ISO 11146 describes this measurement procedure. For other applications, other definitions for the beam diameter can be used. For some quantities used in this International Standard, the first definition (encircled power [energy]) is more appropriate and easier to use.

The International Organization for Standardization (ISO) draws attention to the fact that it is claimed that compliance with this document can involve the use of patents concerning the inclusion of negative noise values in background evaluation of CCD camera images as described in [8.3.2](#).

ISO takes no position concerning the evidence, validity, and scope of this patent right.

The holder of this patent right (U.S. No. 5,418,562 and 5,440,562, and PCT WO 94/27401) has assured ISO that they are willing to negotiate licenses under reasonable and non-discriminatory terms and conditions with applicants throughout the world. In this respect, the statement of the holder of this patent right is registered with ISO. Information can be obtained from:

Spiricon Inc.

Laser Beam Diagnostics

2600 North Main

Logan, UT 84341

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